

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10596973	BAIDEN, GREG
	Examiner	Art Unit
	Hanh Phan	2613

SEARCHED

Class	Subclass	Date	Examiner
398	104, 105, 33, 177, 140, 135, 124, 118, 119, 123, 128, 130	06/16/2010	HP
367	134, 131, 133, 117, 910	06/16/2010	HP

SEARCH NOTES

Search Notes	Date	Examiner
EAST SEARCH SEE ATTACHED PRINTOUT IN THE FILE	06/16/2010	HP
IEEE SEARCH	06/16/2010	HP
JPO SEARCH	06/16/2010	HP

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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